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## Exercise 1: Fourier transform (Written, 6 points)

Given a complex-valued function  $f : \mathbb{R} \to \mathbb{C}$ , the one-dimensional Fourier transformation is defined as

$$\mathcal{F}[f(x)] = \int_{-\infty}^{\infty} \mathrm{d}x \ e^{-ikx} f(x) \equiv \hat{f}(k) \ . \tag{1}$$

a) Show that

$$\mathcal{F}[1] = 2\pi\delta(k) \quad \text{and} \quad \mathcal{F}[\delta(x)] = 1 ,$$
(2)

where  $\delta(q)$  is the Dirac delta function. Use  $\int_{-\infty}^{\infty} dq \ h(q)\delta(q) = h(0)$ .

b) Show that the inverse Fourier transformation is

$$\mathcal{F}^{-1}[\hat{f}(k)] = \int_{-\infty}^{\infty} \frac{\mathrm{d}k}{2\pi} \ e^{ikx} \hat{f}(k) = f(x) \ . \tag{3}$$

c) Show that

$$\mathcal{F}[f(x+a)] = e^{ika} \mathcal{F}[f(x)] .$$
(4)

d) Show that

$$\mathcal{F}[\partial_x f(x)] = ik \ \mathcal{F}[f(x)] \ . \tag{5}$$

e) The convolution of two functions  $f : \mathbb{R} \to \mathbb{C}$  and  $g : \mathbb{R} \to \mathbb{C}$  is defined as

$$(f * g)(x) = \int_{-\infty}^{\infty} d\xi \ f(\xi)g(x - \xi) = \int_{-\infty}^{\infty} d\xi \ f(x - \xi)g(\xi) \ .$$
(6)

Show that

$$\mathcal{F}[(f * g)(x)] = \mathcal{F}[f(x)] \cdot \mathcal{F}[g(x)] .$$
(7)

f) Calculate the Fourier transformation of the Gaussian function

$$f(x) = e^{-ax^2}$$
 with  $a \neq 0$ ,  $\operatorname{Re}(a) \ge 0$ ,  $a \in \mathbb{C}$ . (8)

Pay particular attention to the calculation for a purely imaginary a.

## Exercise 2: Wave packet (Written, 6 points)

We consider a free particle of mass m. Its dispersion relation is  $\omega(k) = \frac{\hbar}{2m}k^2$ . As shown in the lecture, the functions  $\psi_k(x) = e^{i(kx-\omega(k)t)}$  form a basis for the solution space of the Schrödinger equation for the free particle.

One solution of the Schrödinger equation for the free particle is the Gaussian wave packet. At time t = 0, the wave packet is of the form

$$\psi(x,0) = A \, e^{ik_0 x} e^{-\frac{(x-x_0)^2}{4\sigma}} \,. \tag{9}$$

- a) Calculate the normalization constant A.
- b) Show that the wave packet becomes

$$\psi(x,t) = \left(\frac{\sigma}{2\pi\sigma_t^2}\right)^{\frac{1}{4}} e^{ik_0x} e^{-i\frac{\hbar}{2m}k_0^2t} e^{-\frac{(x-(x_0+\hbar k_0t/m))^2}{4\sigma_t}}, \quad \sigma_t = \sigma + i\frac{\hbar}{2m}t$$
(10)

for arbitrary time t.

c) Determine the velocity of the particle which is described by the wave packet. Use the equations

$$\langle v \rangle = \partial_t \langle x \rangle , \quad \langle x \rangle = \int_{-\infty}^{\infty} \mathrm{d}x \, \psi^*(x,t) x \psi(x,t) .$$
 (11)

d) The uncertainty  $\Delta x$  is defined by  $(\Delta x)^2 = \langle x^2 \rangle - \langle x \rangle^2$ . It is a measure of the width of a probability distribution. At t = 0, the uncertainty of the particle's position is given by  $(\Delta x)^2|_{t=0} = \sigma$ . Show that

$$(\Delta x)^2 = \sigma(a_0 + a_1 t^2) \tag{12}$$

for arbitrary time t.

e) A temperature profile T(x,t) is described by the heat equation

$$\partial_t T(x,t) - D\partial_x^2 T(x,t) = 0 , \qquad (13)$$

where D is a real constant. We consider a Gaussian temperature profile with  $(\Delta x)^2|_{t=0} = \sigma$  at t = 0. Show that

$$(\Delta x)^2 = \sigma(b_0 + b_1 t) \tag{14}$$

for arbitrary time t. Take into account that  $\langle x \rangle$  is defined by

$$\langle x \rangle = \int_{-\infty}^{\infty} \mathrm{d}x \, T(x,t)x \;.$$
 (15)

in the context of the heat equation.

The solution of the heat equation can be obtained from the solution of the Schrödinger equation through Wick rotation  $t \rightarrow -it$ . In addition, we must set  $k_0 = 0$  inside the solution of the Schrödinger equation since temperature distributions solely undergo diffusion.

*Remark:* Note the difference between equation 14 and 12, showing that the i inside the Schrödinger equation causes the quadratic broadening.

f) A linear dispersion relation  $\omega(k) = c_0 + c_1 k$  would have changed the results for the free particle. Show that the wave packet would not have broadened in time.

## Exercise 3: Double-slit experiment and uncertainty principle (Oral)

Electrons of momentum  $p_0$  move perpendicularly towards an aperture with two slits of distance a. After passing the aperture, the electrons yield an interference pattern on a screen mounted parallel to the aperture. The distance between the screen and the aperture is d. The angles  $\theta_1$ ,  $\theta_2$  are enclosed by the normal of the screen and the electrons' path drawn from slit 1, 2 to the impact point on the screen.

a) Calculate the positions of the interference maxima on the screen. The probability to find electrons on the screen is

$$P \propto \left|\phi_1 + \phi_2\right|^2 \,, \tag{16}$$

where  $\phi_i$  is the collected phase which can be calculated via

$$\phi_i = e^{\frac{i}{\hbar}S[x_i(t)]}$$
 with  $S[x_i(t)] = \int dt \ L[x_i(t)] = \int dt \ \frac{m}{2} (\partial_t x_i(t))^2$ . (17)

Here,  $x_i(t)$  denotes the electrons' path that passes slit *i*. The angles  $\theta_1$  and  $\theta_2$  can be assumed to be small and treated as equal.

b) In this subtask, we consider a measurement device attached to the slits. The measurement device reveals the slit an electron passes before it hits the screen by the following principle: We treat the scattering of the electrons at the double-slit in a classical picture. The momentum  $\delta p$  transferred on the electron depends on the slit the electron went through. In case of elastic scattering, the momentum transfer is

$$\delta p_i = -p_0 \sin \theta_i \tag{18}$$

for slit i (here, we must not treat  $\theta_1$  and  $\theta_2$  as equal). If we try to measure  $\delta p$ , we have to take into account that the measurement device itself obeys the uncertainty principle

$$\Delta p \Delta x \ge h. \tag{19}$$

The uncertainty  $\Delta p$  of the momentum of the measurement device must fulfill the condition  $\Delta p < |\delta p_2 - \delta p_1|$  in order to be able to discriminate between the two slits. Estimate the uncertainty  $\Delta x$  of the position of the measurement device.

c) Compare the uncertainty of the position of the measurement device with the distance of the interference maxima.